Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/600,390	CHATTERJEE ET AL.	
Examiner	Art Unit	
Leon J. Harper	2166	

SEARCHED				
Class	Subclass	Date	Examiner	
707	104.1,100, 10,7	11/18/2005	LJH	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH (INCLUDING SEAI		EGY)
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